

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/839,707	LAM ET AL.
	Examiner	Art Unit
	Dave T. Nguyen	1632

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
514	44	5/31/2005	DTN
424	450		
435	320.1		
435/455, 458			